

## DTP20N50SJ-VB Datasheet

### N-Channel 500V (D-S) Super Junction Power MOSFET

| PRODUCT SUMMARY                    |                        |
|------------------------------------|------------------------|
| $V_{DS}$ (V) at $T_J$ max.         | 500                    |
| $R_{DS(on)}$ at 25 °C ( $\Omega$ ) | $V_{GS} = 10$ V   0.14 |
| $Q_g$ max. (nC)                    | 92                     |
| $Q_{gs}$ (nC)                      | 10                     |
| $Q_{gd}$ (nC)                      | 19                     |
| Configuration                      | Single                 |

#### FEATURES

- Low figure-of-merit (FOM)  $R_{on} \times Q_g$
- Low input capacitance ( $C_{iss}$ )
- Reduced switching and conduction losses
- Low gate charge ( $Q_g$ )
- Avalanche energy rated (UIS)

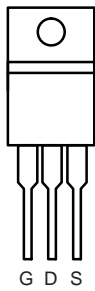


RoHS  
COMPLIANT  
HALOGEN  
FREE

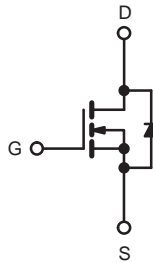
#### APPLICATIONS

- Switch mode power supplies (SMPS)
- Server and telecom power supplies
- Power factor correction power supplies (PFC)

TO-220AB



G D S  
Top View




N-Channel MOSFET

| ABSOLUTE MAXIMUM RATINGS ( $T_C = 25$ °C, unless otherwise noted) |                                 |                |      |   |
|---|---------------------------------|----------------|------|---|
| PARAMETER   | SYMBOL                          | LIMIT          | UNIT |   |
| Drain-Source Voltage  | $V_{DS}$                        | 500            | V    |   |
| Gate-Source Voltage   | $V_{GS}$                        | $\pm 30$       |      |   |
| Continuous Drain Current ( $T_J = 150$ °C)                        | $V_{GS}$ at 10 V                | $T_C = 25$ °C  | 20   | A |
|   |                                 | $T_C = 100$ °C | 12   |   |
| Pulsed Drain Current <sup>a</sup>                                 | $I_{DM}$                        | 42             |      |   |
| Linear Derating Factor  |                                 | 1.4            | W/°C |   |
| Single Pulse Avalanche Energy <sup>b</sup>                        | $E_{AS}$                        | 204            | mJ   |   |
| Maximum Power Dissipation   | $P_D$                           | 179            | W    |   |
| Operating Junction and Storage Temperature Range                  | $T_J, T_{stg}$                  | -55 to +150    | °C   |   |
| Drain-Source Voltage Slope  | $V_{DS} = 0$ V to 80 % $V_{DS}$ | 70             | V/ns |   |
| Reverse Diode dV/dt <sup>d</sup>                                  |                                 | 32             |      |   |
| Soldering Recommendations (Peak Temperature) <sup>c</sup>         | for 10 s                        | 300            | °C   |   |

#### Notes

- Repetitive rating; pulse width limited by maximum junction temperature.
- $V_{DD} = 50$  V, starting  $T_J = 25$  °C,  $L = 28.2$  mH,  $R_g = 25$   $\Omega$ ,  $I_{AS} = 3.8$  A.
- 1.6 mm from case.
- $I_{SD} \leq I_D$ ,  $dI/dt = 100$  A/ $\mu$ s, starting  $T_J = 25$  °C.

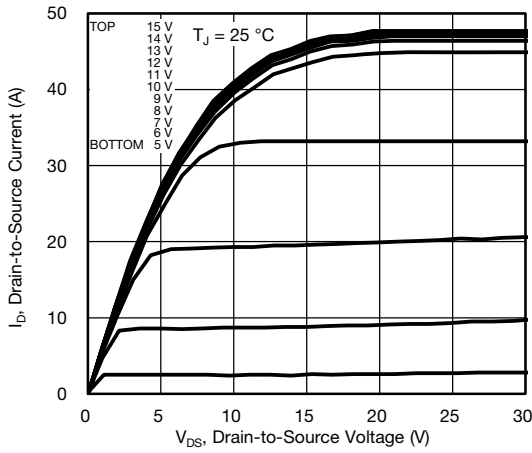
| THERMAL RESISTANCE RATINGS       |            |      |      |      |
|----------------------------------|------------|------|------|------|
| PARAMETER                        | SYMBOL     | TYP. | MAX. | UNIT |
| Maximum Junction-to-Ambient      | $R_{thJA}$ | -    | 62   | °C/W |
| Maximum Junction-to-Case (Drain) | $R_{thJC}$ | -    | 0.7  |      |

| SPECIFICATIONS (T <sub>J</sub> = 25 °C, unless otherwise noted) |                                  |   |  |                       |      |       |      |
|---|----------------------------------|---|--|-----------------------|------|-------|------|
| PARAMETER   | SYMBOL                           | TEST CONDITIONS   |  | MIN.                  | TYP. | MAX.  | UNIT |
| <b>Static</b>   |                                  |   |  |                       |      |       |      |
| Drain-Source Breakdown Voltage                                  | V <sub>DS</sub>                  | V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA  |  | 500                   | -    | -     | V    |
| V <sub>DS</sub> Temperature Coefficient                         | ΔV <sub>DS</sub> /T <sub>J</sub> | Reference to 25 °C, I <sub>D</sub> = 1 mA   |  | -                     | 0.59 | -     | V/°C |
| Gate-Source Threshold Voltage (N)                               | V <sub>GS(th)</sub>              | V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA   |  | 2.0                   | -    | 4.0   | V    |
| Gate-Source Leakage   | I <sub>GSS</sub>                 | V <sub>GS</sub> = ± 20 V  |  | -                     | -    | ± 100 | nA   |
|   |                                  | V <sub>GS</sub> = ± 30 V  |  | -                     | -    | ± 1   | μA   |
| Zero Gate Voltage Drain Current                                 | I <sub>DSS</sub>                 | V <sub>DS</sub> = 500 V, V <sub>GS</sub> = 0 V  |  | -                     | -    | 1     | μA   |
|   |                                  | V <sub>DS</sub> = 400 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C   |  | -                     | -    | 10    |      |
| Drain-Source On-State Resistance                                | R <sub>DS(on)</sub>              | V <sub>GS</sub> = 10 V  | I <sub>D</sub> = 10 A                          | -                     | 0.14 | -     | Ω    |
| Forward Transconductance  | g <sub>fs</sub>                  | V <sub>DS</sub> = 30 V, I <sub>D</sub> = 10 A   |  | -                     | 4.4  | -     | S    |
| <b>Dynamic</b>  |                                  |   |  |                       |      |       |      |
| Input Capacitance   | C <sub>iss</sub>                 | V <sub>GS</sub> = 0 V,<br>V <sub>DS</sub> = 100 V,<br>f = 1 MHz   |  | -                     | 1640 | -     | pF   |
| Output Capacitance  | C <sub>oss</sub>                 |   |  | -                     | 87   | -     |      |
| Reverse Transfer Capacitance                                    | C <sub>rss</sub>                 |   |  | -                     | 6    | -     |      |
| Effective Output Capacitance, Energy Related <sup>a</sup>       | C <sub>o(er)</sub>               |   |  | -                     | 73   | -     |      |
| Effective Output Capacitance, Time Related <sup>b</sup>         | C <sub>o(tr)</sub>               | V <sub>DS</sub> = 0 V to 400 V, V <sub>GS</sub> = 0 V   |  | -                     | 222  | -     |      |
| Total Gate Charge   | Q <sub>g</sub>                   | V <sub>GS</sub> = 10 V  | I <sub>D</sub> = 10 A, V <sub>DS</sub> = 400 V | -                     | 46   | 92    | nC   |
| Gate-Source Charge  | Q <sub>gs</sub>                  |   |  | -                     | 10   | -     |      |
| Gate-Drain Charge   | Q <sub>gd</sub>                  |   |  | -                     | 19   | -     |      |
| Turn-On Delay Time  | t <sub>d(on)</sub>               | V <sub>DD</sub> = 400 V, I <sub>D</sub> = 10 A,<br>V <sub>GS</sub> = 10 V, R <sub>g</sub> = 9.1 Ω   |  | -                     | 17   | 34    | ns   |
| Rise Time   | t <sub>r</sub>                   |   |  | -                     | 27   | 54    |      |
| Turn-Off Delay Time   | t <sub>d(off)</sub>              |   |  | -                     | 48   | 96    |      |
| Fall Time   | t <sub>f</sub>                   |   |  | -                     | 25   | 50    |      |
| Gate Input Resistance   | R <sub>g</sub>                   |   |  | f = 1 MHz, open drain |      | -     |      |
| <b>Drain-Source Body Diode Characteristics</b>                  |                                  |   |  |                       |      |       |      |
| Continuous Source-Drain Diode Current                           | I <sub>S</sub>                   | MOSFET symbol showing the integral reverse p - n junction diode  |  | -                     | -    | 20    | A    |
| Pulsed Diode Forward Current                                    | I <sub>SM</sub>                  |   |  | -                     | -    | 42    |      |
| Diode Forward Voltage   | V <sub>SD</sub>                  | T <sub>J</sub> = 25 °C, I <sub>S</sub> = 10 A, V <sub>GS</sub> = 0 V  |  | -                     | -    | 1.2   | V    |
| Reverse Recovery Time   | t <sub>rr</sub>                  | T <sub>J</sub> = 25 °C, I <sub>F</sub> = I <sub>S</sub> = 10 A,<br>di/dt = 100 A/μs, V <sub>R</sub> = 25 V  |  | -                     | 293  | -     | ns   |
| Reverse Recovery Charge   | Q <sub>rr</sub>                  |   |  | -                     | 4.0  | -     | μC   |
| Reverse Recovery Current  | I <sub>RRM</sub>                 |   |  | -                     | 26   | -     | A    |

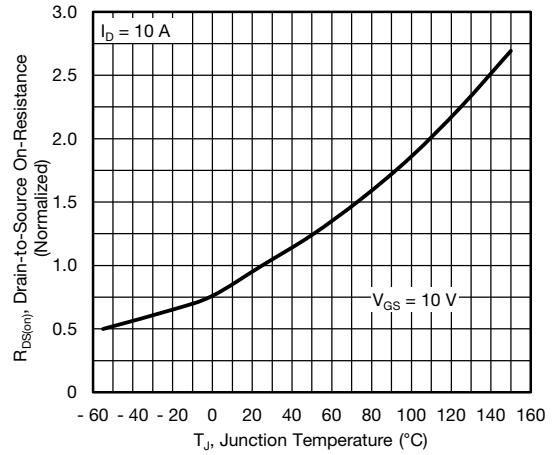
**Notes**

- a. C<sub>oss(er)</sub> is a fixed capacitance that gives the same energy as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 % to 80 % V<sub>DSS</sub>.
- b. C<sub>oss(tr)</sub> is a fixed capacitance that gives the same charging time as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 % to 80 % V<sub>DSS</sub>.

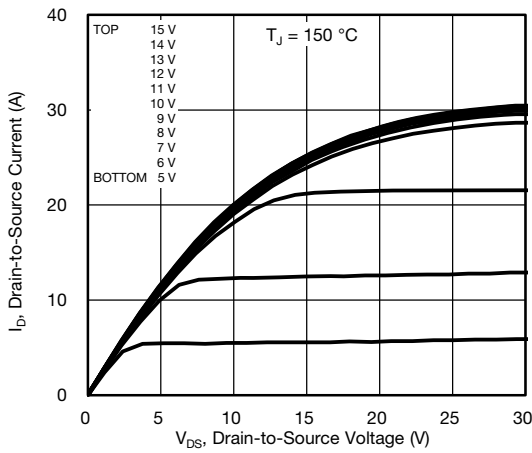
**TYPICAL CHARACTERISTICS** (25 °C, unless otherwise noted)



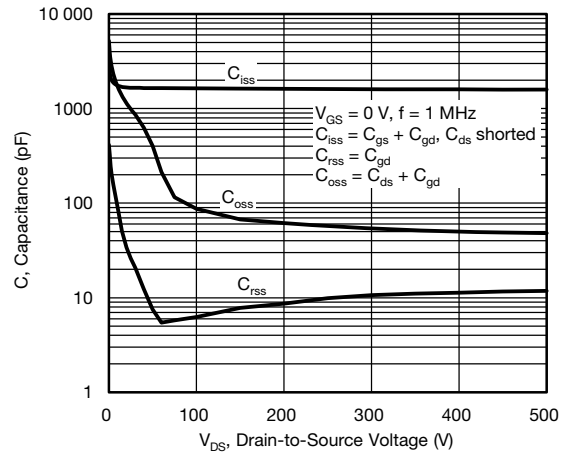
**Fig. 1 - Typical Output Characteristics**



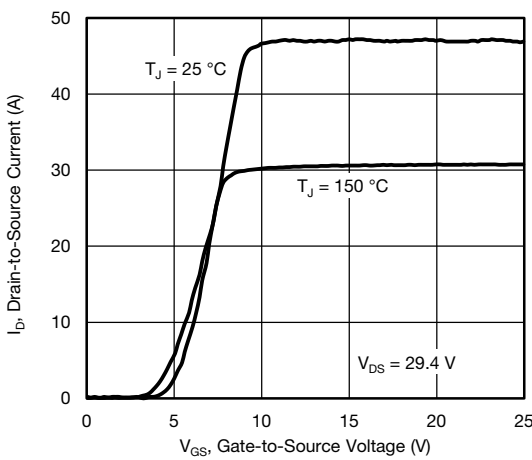
**Fig. 4 - Normalized On-Resistance vs. Temperature**



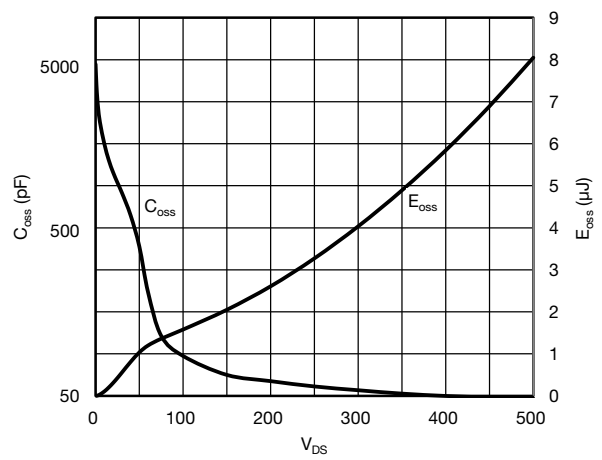
**Fig. 2 - Typical Output Characteristics**



**Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage**



**Fig. 3 - Typical Transfer Characteristics**



**Fig. 6 - C<sub>OSS</sub> and E<sub>OSS</sub> vs. V<sub>DS</sub>**

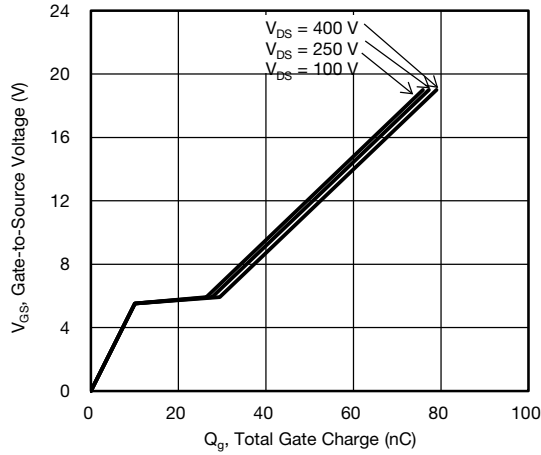


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

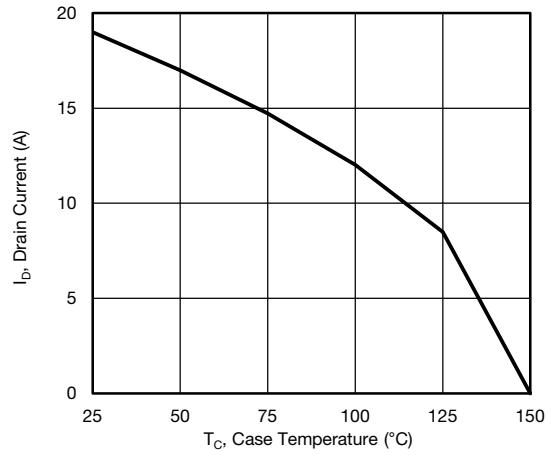


Fig. 10 - Maximum Drain Current vs. Case Temperature

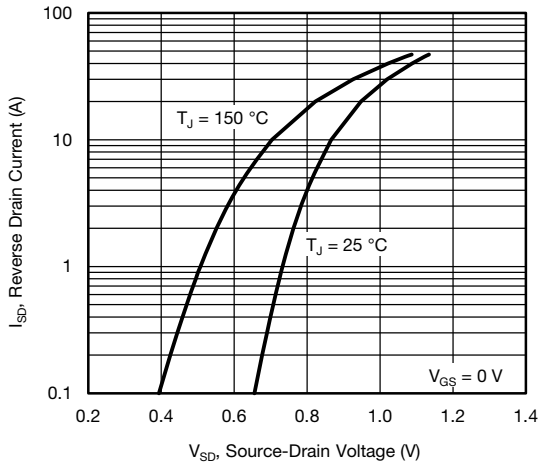


Fig. 8 - Typical Source-Drain Diode Forward Voltage

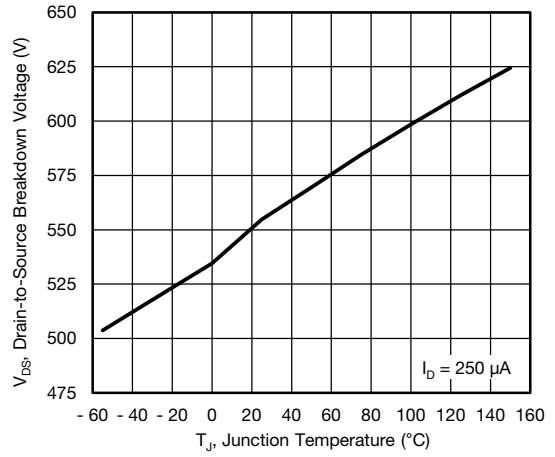


Fig. 11 - Temperature vs. Drain-to-Source Voltage

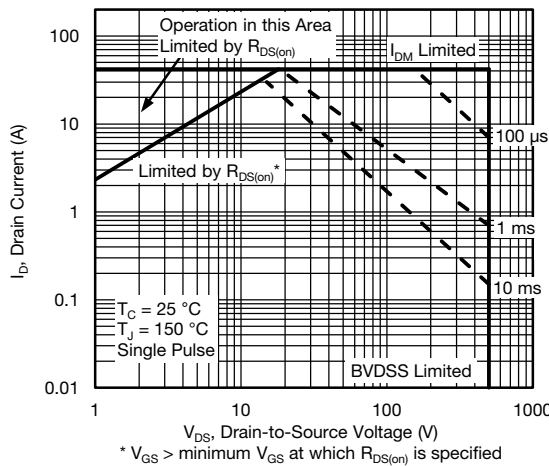
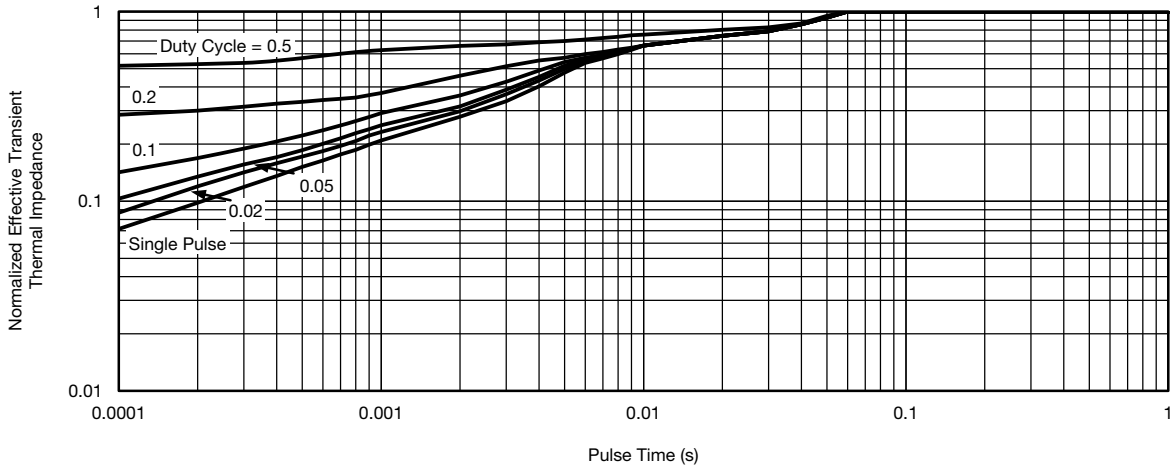
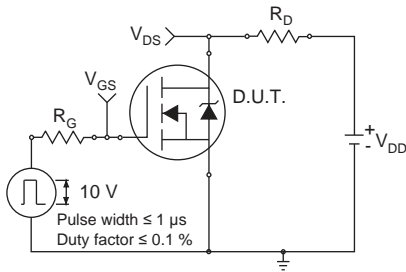


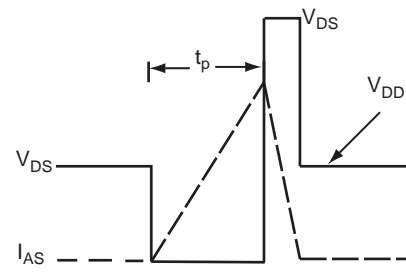
Fig. 9 - Maximum Safe Operating Area



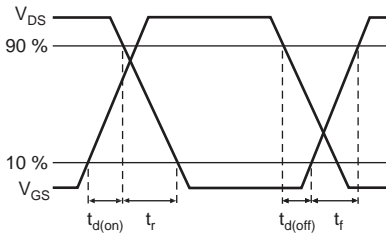
**Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case**



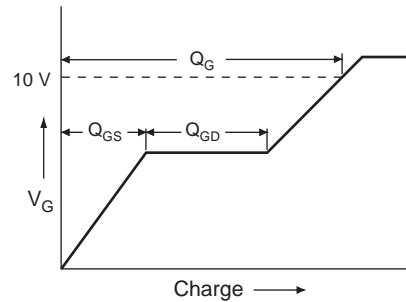
**Fig. 13 - Switching Time Test Circuit**



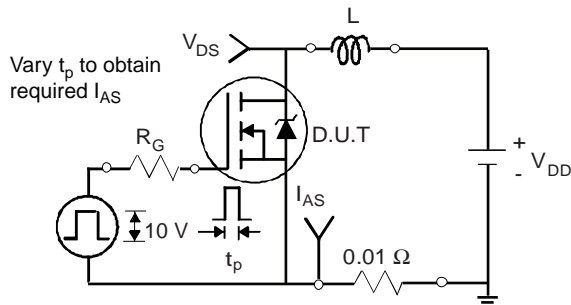
**Fig. 16 - Unclamped Inductive Waveforms**



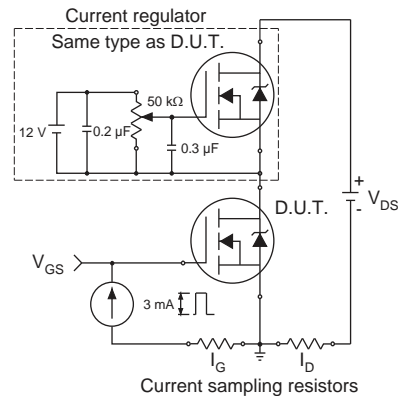
**Fig. 14 - Switching Time Waveforms**



**Fig. 17 - Basic Gate Charge Waveform**

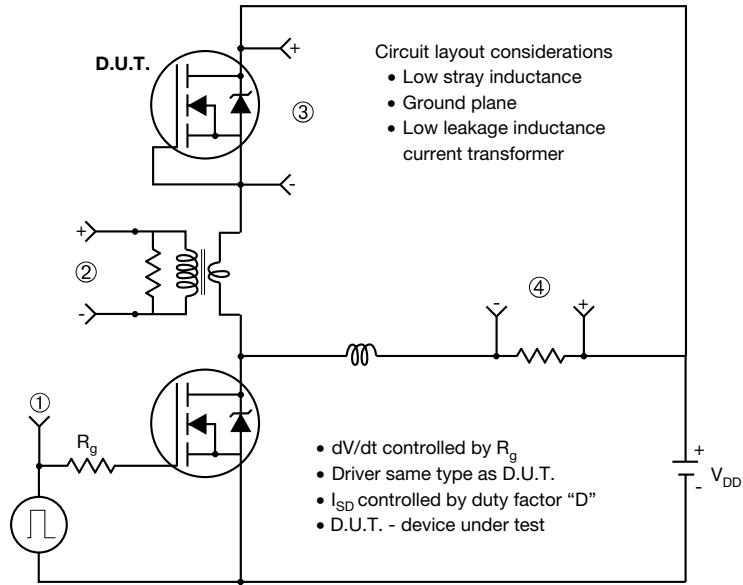


**Fig. 15 - Unclamped Inductive Test Circuit**



**Fig. 18 - Gate Charge Test Circuit**

**Peak Diode Recovery dV/dt Test Circuit**

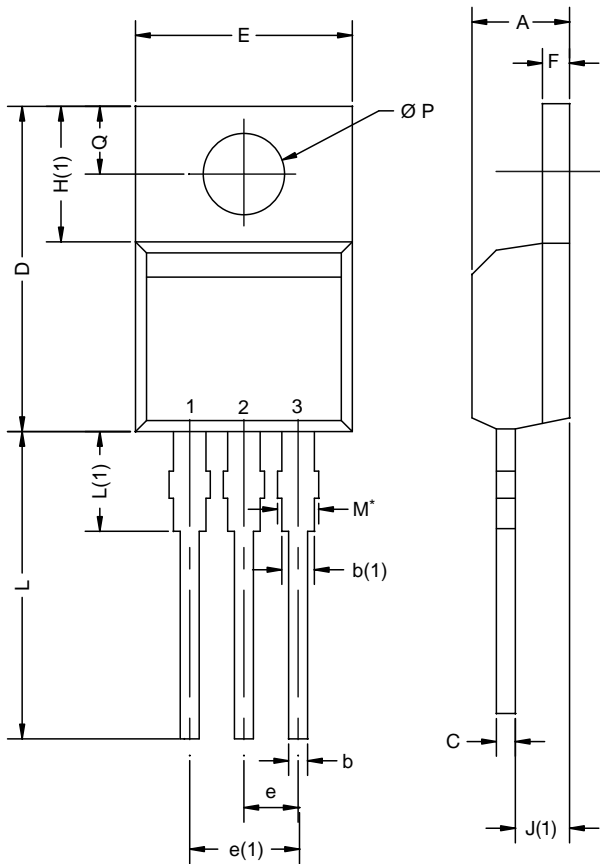


**Note**

a.  $V_{GS} = 5 V$  for logic level devices

**Fig. 19 - For N-Channel**

TO-220AB



| DIM. | MILLIMETERS |       | INCHES |       |
|------|-------------|-------|--------|-------|
|      | MIN.        | MAX.  | MIN.   | MAX.  |
| A    | 4.25        | 4.65  | 0.167  | 0.183 |
| b    | 0.69        | 1.01  | 0.027  | 0.040 |
| b(1) | 1.20        | 1.73  | 0.047  | 0.068 |
| c    | 0.36        | 0.61  | 0.014  | 0.024 |
| D    | 14.85       | 15.49 | 0.585  | 0.610 |
| E    | 10.04       | 10.51 | 0.395  | 0.414 |
| e    | 2.41        | 2.67  | 0.095  | 0.105 |
| e(1) | 4.88        | 5.28  | 0.192  | 0.208 |
| F    | 1.14        | 1.40  | 0.045  | 0.055 |
| H(1) | 6.09        | 6.48  | 0.240  | 0.255 |
| J(1) | 2.41        | 2.92  | 0.095  | 0.115 |
| L    | 13.35       | 14.02 | 0.526  | 0.552 |
| L(1) | 3.32        | 3.82  | 0.131  | 0.150 |
| Ø P  | 3.54        | 3.94  | 0.139  | 0.155 |
| Q    | 2.60        | 3.00  | 0.102  | 0.118 |

ECN: X12-0208-Rev. N, 08-Oct-12  
DWG: 5471

Notes

\* M = 1.32 mm to 1.62 mm (dimension including protrusion)  
Heatsink hole for HVM

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